Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,372	KOERTZEN ET AL.
Examiner	Art Unit
James K. Trujillo	2116

SEARCHED					
Class	Subclass	Date	Examiner		
	•	-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

(INCLUDING SEARCH	SIRAIEGI)
	DATE	EXMR
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	7/20/2006	, JKT
Updated	12/15/2006	JKT
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